L	Hits	Search Text	DB	Time stamp
Number	11.00	714/7201-	HCD3m-	2004/00/27
1	1169	714/738.ccls.	USPAT; US-PGPUB;	2004/09/27 15:42
			EPO; JPO;	13.42
			DERWENT;	
			IBM_TDB	
2	2		USPAT;	2004/09/27
		circuit\$1) and semiconductor and test\$3	US-PGPUB;	15:45
		and (transmi\$5 with parallel with serial) and (receiv\$3 with serial with parallel)	EPO; JPO; DERWENT;	
		and (test\$3 with generat\$3) and compar\$5	IBM TDB	
3	2		USPAT;	2004/09/27
		circuit\$1) or IC)and semiconductor and	US-PGPUB;	15:43
		test\$3 and (transmi\$5 with parallel with	EPO; JPO;	
		serial) and (receiv\$3 with serial with	DERWENT;	
		parallel) and (test\$3 with generat\$3) and compar\$5	IBM_TDB	
4	15	l • '	USPAT;	2004/09/27
		semiconductor and test\$3 and (transmi\$5	US-PGPUB;	15:47
		with parallel with serial) and (receiv\$3	EPO; JPO;	
		with serial with parallel) and (test\$3	DERWENT;	
		with generat\$3) and compar\$5 and (test\$3 adj mode) and (loopback)	IBM_TDB	
5	2		USPAT;	2004/09/27
	_	circuit\$1) and semiconductor and test\$3	US-PGPUB;	15:46
:		and (transmi\$5 with parallel with serial)	EPO; JPO;	
:	•	and (receiv\$3 with serial with parallel)	DERWENT;	
6	0	and (test\$3 with generat\$3) and compar\$5 (713/400.ccls.) and ((integrated adj	IBM_TDB USPAT;	2004/09/27
"	0	circuit\$1) or IC) and semiconductor and	US-PGPUB;	15:49
		test\$3 and (transmi\$5 with parallel with	EPO; JPO;	10.13
		serial) and (receiv\$3 with serial with	DERWENT;	
		parallel) and (test\$3 with generat\$3) and	IBM_TDB	
		compar\$5 and (test\$3 adj mode) and (loopback)		
7	2	(375/221.ccls.) and ((integrated adj	USPAT;	2004/09/27
, ·	_	circuit\$1) or IC) and semiconductor and	US-PGPUB;	15:50
		test\$3 and (transmi\$5 with parallel with	EPO; JPO;	
		serial) and (receiv\$3 with serial with	DERWENT;	
		parallel) and (test\$3 with generat\$3) and compar\$5 and (test\$3 adj mode) and	IBM_TDB	
		(loopback)		
8	0	(324/763.ccls.) and ((integrated adj	USPAT;	2004/09/27
		circuit\$1) or IC) and semiconductor and	US-PGPUB;	15:50
		test\$3 and (transmi\$5 with parallel with	EPO; JPO;	
		serial) and (receiv\$3 with serial with parallel) and (test\$3 with generat\$3) and	DERWENT; IBM TDB	
		compar\$5 and (test\$3 with generat\$3) and compar\$5 and (test\$3 adj mode) and	TEM_TOD	
		(loopback)		
10	2	(370/249.ccls.) and ((integrated adj	USPAT;	2004/09/27
		circuit\$1) or IC) and semiconductor and	US-PGPUB;	15:51
		test\$3 and (transmi\$5 with parallel with	EPO; JPO;	
		serial) and (receiv\$3 with serial with parallel) and (test\$3 with generat\$3) and	DERWENT; IBM TDB	
		compar\$5 and (test\$3 adj mode) and		
		(loopback)		